Search Notes

Application/Control No.	Applicant(s)/Patent Under Reexamination
10598668	TSUCHIYA ET AL.
Examiner	Art Unit
Louis K Huynh	3721

SEARCHED					
Class	Subclass	Date	Examiner		
53	220, 223, 224, 228, 230, 231, 232	10/10/2008	LH		

SEARCH NOTES				
Search Notes	Date	Examiner		
INTERFERENCE SEAR	СН			

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	INTERFERENCE SEA	RCH	
Class	Subclass	Date	Examin
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U.S. Patent and Trademark Office Part of Paper No.: 20080930